


<b>Search Notes</b> 	<b>Application/Control No.</b> 10065546	<b>Applicant(s)/Patent Under Reexamination</b> NEIMAN ET AL.
	<b>Examiner</b> Wai, Eric C	<b>Art Unit</b> 2195

SEARCHED			
Class	Subclass	Date	Examiner
718	105	12/13/2006	ECW
709	104	12/13/2006	ECW

SEARCH NOTES		
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Inventor's Name Search	12/13/2006	ECW
East Search	12/13/2006	ECW

INTERFERENCE SEARCH			
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